

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/005,030	TSARFATI, YORAM	
		Examiner	Art Unit	Page 1 of 2
		Satish S. Rampuria	2124	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0015809 A1	01-2004	Cheng, Doreen Yining	717/100
	B	US-5,278,986 A	01-1994	Jourdenais et al.	717/149
	C	US-6,243,809 B1	06-2001	Gibbons et al.	713/1
	D	US-5,933,641 A	08-1999	Ma, Wei	717/143
	E	US-2003/0212983 A1	11-2003	Tinker, Jeffrey L.	717/110
	F	US-2003/0084434 A1	05-2003	Ren, Yuqing	717/172
	G	US-6,260,077 B1	07-2001	Rangarajan et al.	719/328
	H	US-5,504,903 A	04-1996	Chen et al.	713/1
	I	US-2004/0031030 A1	02-2004	Kidder et al.	717/172
	J	US-2001/0052006 A1	12-2001	BARKER et al.	709/223
	K	US-6,182,157 B1	01-2001	Schliener et al.	719/318
	L	US-2003/0009711 A1	01-2003	Kuhn et al.	714/57
	M	US-6,701,513 B1	03-2004	Bailey, Bendrix L.	717/109

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
	U	Bell et al., Bridging the gap between embedded test and ATE, Test Conference, 2000. Proceedings. International , 3-5 Oct. 2000, Pages:55 - 63
	V	Leupers, Code generation for embedded processors, System Synthesis, 2000. Proceedings. The 13th International Symposium on , 20-22 Sept. 2000, Pages:173 - 178
	W	Gauthier et al, Automatic generation and targeting of application-specific operating systems and embedded systems software, Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on , Volume: 20 , Issue: 11 , Nov. 2001, Pages:1293-1301
	X	Sun.com, Solstice Telecommunications Management, Oct 17, 2001, www.sun.com/software.../index.html , pages 1-21

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0133812	09-2002	Little et al.	717/140
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
	R					
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	U	
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